

## **Ordering Information**

Part Number	Ambient Temperature Range	Package	Environmental		
AOZ8235DI-05	-40 °C to +85 °C	DFN 1.45 x 1.0	Green Product RoHS Compliant		



AOS Green Products use reduced levels of Halogens, and are also RoHS compliant.

Please visit www.aosmd.com/media/AOSGreenPolicy.pdf for additional information.

### **Absolute Maximum Ratings**

Exceeding the Absolute Maximum ratings may damage the device.

Parameter	Rating		
VP – VN	5 V		
Peak Pulse Current (I <sub>PP</sub> ), t <sub>P</sub> = 8/20 μs	4 A		
Storage Temperature (T <sub>S</sub> )	-65 °C to +150 °C		
ESD Rating per IEC61000-4-2, Contact <sup>(1)</sup>	±18 kV		
ESD Rating per IEC61000-4-2, Air <sup>(1)</sup>	±18 kV		
ESD Rating per Human Body Model <sup>(2)</sup>	±30 kV		

Notes:

1. IEC 61000-4-2 discharge with C<sub>Discharge</sub> = 150 pF, R<sub>Discharge</sub> = 330  $\Omega$ .

2. Human Body Discharge per MIL-STD-883, Method 3015 C<sub>Discharge</sub> = 100 pF, R<sub>Discharge</sub> = 1.5 k $\Omega$ .

## **Maximum Operating Ratings**

Parameter	Rating		
Junction Temperature (T <sub>J</sub> )	-40 °C to +125 °C		

### **Electrical Characteristics**

 $T_A = 25^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
V <sub>RWM</sub>	Reverse Working Voltage	Between pin 5 and 2 <sup>(3)</sup>			5.0	V
V <sub>BR</sub>	Reverse Breakdown Voltage	$I_T = 1 \text{ mA}$ , between pins 5 and $2^{(4)}$	6.0			V
I <sub>R</sub>	Reverse Leakage Current	V <sub>RWM</sub> = 5 V, any I/O pin to Ground			0.1	μA
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 10 mA, any I/O pin to Ground		0.7		V
V <sub>CL</sub>	Channel Clamp Voltage Positive Transients Negative Transient	I <sub>PP</sub> = 15 A, tp = 100 ns, any I/O pin to Ground			12.0 -10.0	V V
	Channel Clamp Voltage Positive Transients Negative Transient	I <sub>PP</sub> = 25 A, tp = 100 ns, any I/O pin to Ground			15.0 -18.0	V V
Cj	Junction Capacitance	V <sub>R</sub> = 0 V, f = 1 MHz, any I/O pin to Ground		13.5	16.0	pF

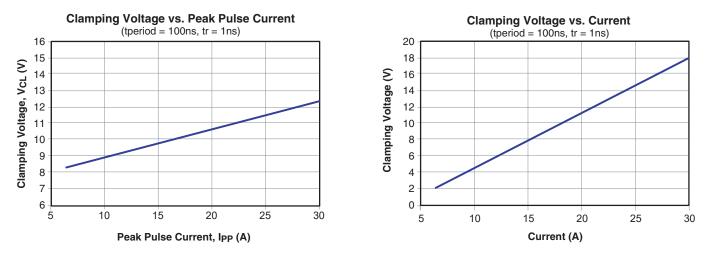
#### Notes:

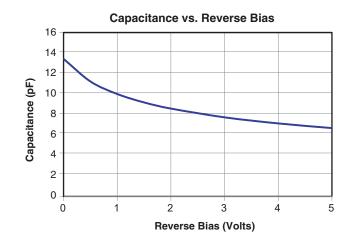
3. The working peak reverse voltage, V<sub>RWM</sub>, should be equal to or greater than the DC or continuous peak operating voltage level.

4.  $V_{BR}$  is measured at the pulse test current I<sub>T</sub>.



# **Typical Performance Characteristics**





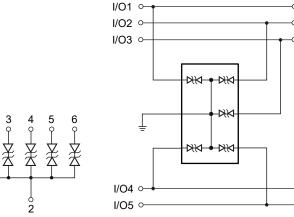


### **Applications Information**

#### Device Connection for Protection of Five Unidirectional Data Lines

These devices are designed to protect up to five unidirectional data lines. The device is connected as follows.

 Unidirectional protection of five I/O lines is achieved by connecting pins 1, 3, 4, 5 and 6 to the data lines. Connect pin 2 to ground. The ground connection should be made directly to the ground plane for best results. The path length is kept as short as possible to reduce the effects of parasitic inductance in the board traces.



Circuit Diagram

Protection of Five Unidirectional Lines

#### Device Connection for Protection of Four Bidirectional Data Lines

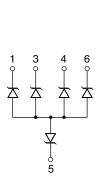
These devices are designed to protect up to four bidirectional data lines. The device is connected as follows.

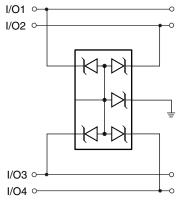
 Bidirectional protection of four I/O lines is achieved by connecting pins 1, 3, 4, and 6 to the data lines. Connect pin 5 to ground. The ground connection should be made directly to the ground plane for best results. The path length is kept as short as possible to reduce the effects of parasitic inductance in the board traces.

#### Circuit Board Layout Recommendations for Suppression of ESD

Good circuit board layout is critical for the suppression of ESD induced transients. The following guidelines are recommended:

- Place the TVS near the input terminals or connectors to restrict transient coupling.
- Minimize the path length between the TVS and the protected line.
- Minimize all conductive loops including power and ground loops.
- The ESD transient return path to ground should be kept as short as possible.
- Never run critical signals near board edges.
- Use ground planes whenever possible.

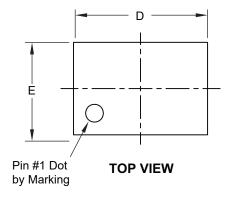


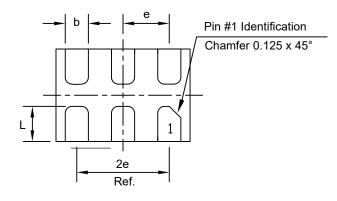


Circuit Diagram

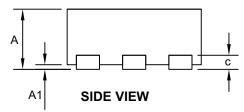
**Protection of Four Bidirectional Lines** 

# Package Dimensions, DFN 1.45 x 1.0, 6L



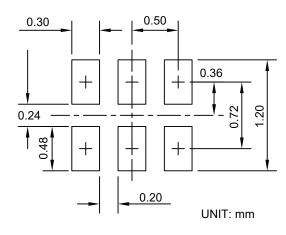


**BOTTOM VIEW** 



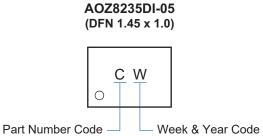
Dimensions in millimeters				Dimensions in inches			
Symbols	Min.	Nom.	Max.	Symbols	Min.	Nom.	Max.
A	0.50	0.55	0.60	А	0.020	0.022	0.024
A1	0.00	—	0.05	A1	0.000	_	0.002
b	0.20	0.25	0.30	b	0.008	0.010	0.012
С	0.152 Ref.			с	0.006 Ref.		
D	1.40	1.45	1.50	D	0.055	0.057	0.059
E	0.95	1.00	1.05	E	0.038	0.040	0.042
е	0.50 BSC			е	0.020 BSC		
L	0.33	0.38	0.43	L	0.013	0.015	0.017

### **RECOMMENDED LAND PATTERN**





## Part Marking



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